

*Product Specification*

**FEATURES**

- Six edge-triggered D-type flip-flops
- Buffered common Clock
- Buffered, asynchronous Master Reset

**DESCRIPTION**

The 74F174 has six edge-triggered D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) and Master Reset ( $\overline{MR}$ ) inputs load and reset (clear) all flip-flops simultaneously.

The register is fully edge-triggered. The state of each D input, one setup time before the Low-to-High clock transition is transferred to the corresponding flip-flop's Q output.

All Q outputs will be forced Low independent of Clock or Data inputs by a Low voltage level on the  $\overline{MR}$  input. The device is useful for applications where true outputs only are required, and the Clock and Master Reset are common to all storage elements.

TYPE	TYPICAL $f_{MAX}$	TYPICAL SUPPLY CURRENT (TOTAL)
74F174	100 MHz	35 mA

**ORDERING INFORMATION**

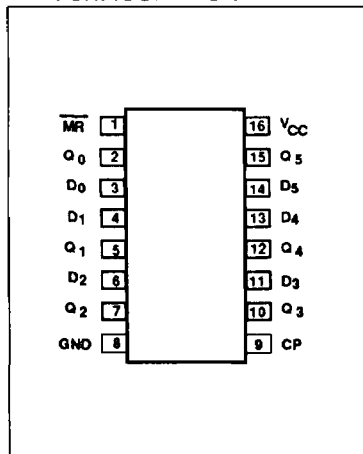
PACKAGES	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$ ; $T_A = 0^\circ C$ to $+70^\circ C$
16-Pin Plastic DIP	N74F174N
16-Pin Plastic SO	N74F174D

**INPUT AND OUTPUT LOADING AND FAN-OUT TABLE**

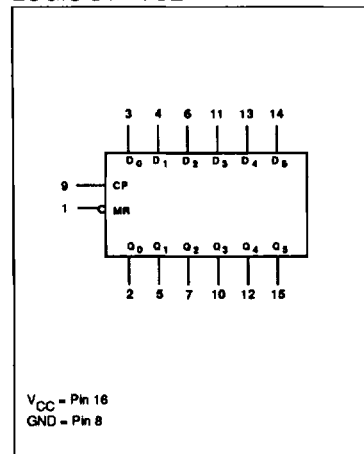
PINS	DESCRIPTION	74ALS(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
$D_0 - D_5$	Data inputs	1.0/1.0	20 $\mu$ A/0.6mA
CP	Clock Pulse input (active rising edge)	1.0/1.0	20 $\mu$ A/0.6mA
$\overline{MR}$	Master Reset input (active-Low)	1.0/1.0	20 $\mu$ A/0.6mA
$Q_0 - Q_5$	Outputs	50/33	1.0mA/20mA

**NOTE:**  
One (1.0) FAST Unit Load is defined as: 20 $\mu$ A in the High state and 0.6mA in the Low state.

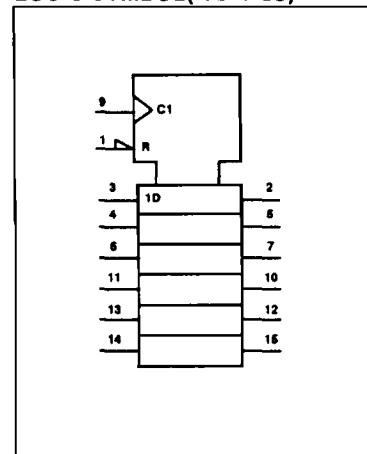
**PIN CONFIGURATION**



**LOGIC SYMBOL**



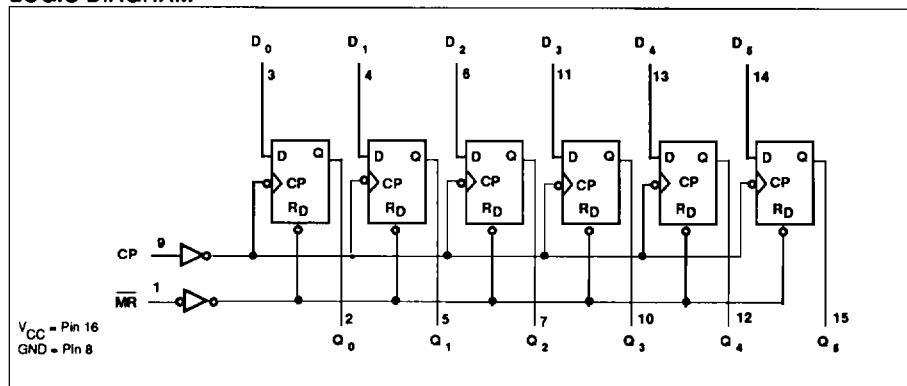
**LOGIC SYMBOL (IEEE/IEC)**



# Flip-Flop

FAST 74F174

## LOGIC DIAGRAM



## FUNCTION TABLE

I INPUTS			OUTPUTS	OPERATING MODE
$\overline{MR}$	CP	D	$Q_n$	
L	X	X	L	Reset (clear) Load "1" Load "0"
H	$\uparrow$	h	H	
H	$\uparrow$	l	L	

H = High voltage level

L = Low voltage level

X = Don't care

$\uparrow$  = Low-to-High Clock transition

h = High voltage level one set-up time prior to the Low-to-High Clock transition.

l = Low voltage level one set-up time prior to the Low-to-High Clock transition.

## ABSOLUTE MAXIMUM RATINGS (Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
$V_{CC}$	Supply voltage	-0.5 to +7.0	V
$V_{IN}$	Input voltage	-0.5 to +7.0	V
$I_{IN}$	Input current	-30 to +5	mA
$V_{OUT}$	Voltage applied to output in High output state	-0.5 to + $V_{CC}$	V
$I_{OUT}$	Current applied to output in Low output state	40	mA
$T_A$	Operating free-air temperature range	0 to +70	°C
$T_{STG}$	Storage temperature	-65 to +150	°C

## RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
$V_{CC}$	Supply voltage	4.5	5.0	5.5	V
$V_{IH}$	High-level input voltage	2.0			V
$V_{IL}$	Low-level input voltage			0.8	V
$I_{IK}$	Input clamp current			-18	mA
$I_{OH}$	High-level output current			-1	mA
$I_{OL}$	Low-level output current			20	mA
$T_A$	Operating free-air temperature range	0		70	°C

## Flip-Flop

FAST 74F174

**DC ELECTRICAL CHARACTERISTICS** (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS <sup>1</sup>	LIMITS			UNIT
			Min	Typ <sup>2</sup>	Max	
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IL</sub> = MAX	±10%V <sub>CC</sub>	2.5		V
		V <sub>IH</sub> = MIN, I <sub>OH</sub> = MAX	±5%V <sub>CC</sub>	2.7	3.4	V
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IL</sub> = MAX	±10%V <sub>CC</sub>		0.30 0.50	V
		V <sub>IH</sub> = MIN, I <sub>OL</sub> = MAX	±5%V <sub>CC</sub>		0.30 0.50	V
V <sub>IK</sub>	Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = I <sub>IK</sub>		-0.73	-1.2	V
I <sub>I</sub>	Input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 7.0V			100	μA
I <sub>IH</sub>	High-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7V			20	μA
I <sub>IL</sub>	Low-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.5V			-0.6	mA
I <sub>OS</sub>	Short circuit output current <sup>3</sup>	V <sub>CC</sub> = MAX		-60	-150	mA
I <sub>CC</sub>	Supply current (total)	V <sub>CC</sub> = MAX, D <sub>n</sub> = $\overline{MR}$ = 4.5V, CP = ↑		35	45	mA

**NOTES:**

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C.
- Not more than one output should be shorted at a time. For testing I<sub>OS</sub>, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter test, I<sub>OS</sub> tests should be performed last.

**AC ELECTRICAL CHARACTERISTICS**

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT
			T <sub>A</sub> = +25°C			T <sub>A</sub> = 0°C to +70°C			
			Min	Typ	Max	Min	Max		
f <sub>MAX</sub>	Maximum clock frequency	Waveform 1	80	100		80			MHz
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay CP to Q <sub>n</sub>	Waveform 1	3.5	5.5	8.0	3.5	9.0		ns
			4.5	6.0	10.0	4.5	11.0		
t <sub>PHL</sub>	Propagation delay MR to Q <sub>n</sub>	Waveform 2	5.0	8.5	14.0	5.0	15.0		ns

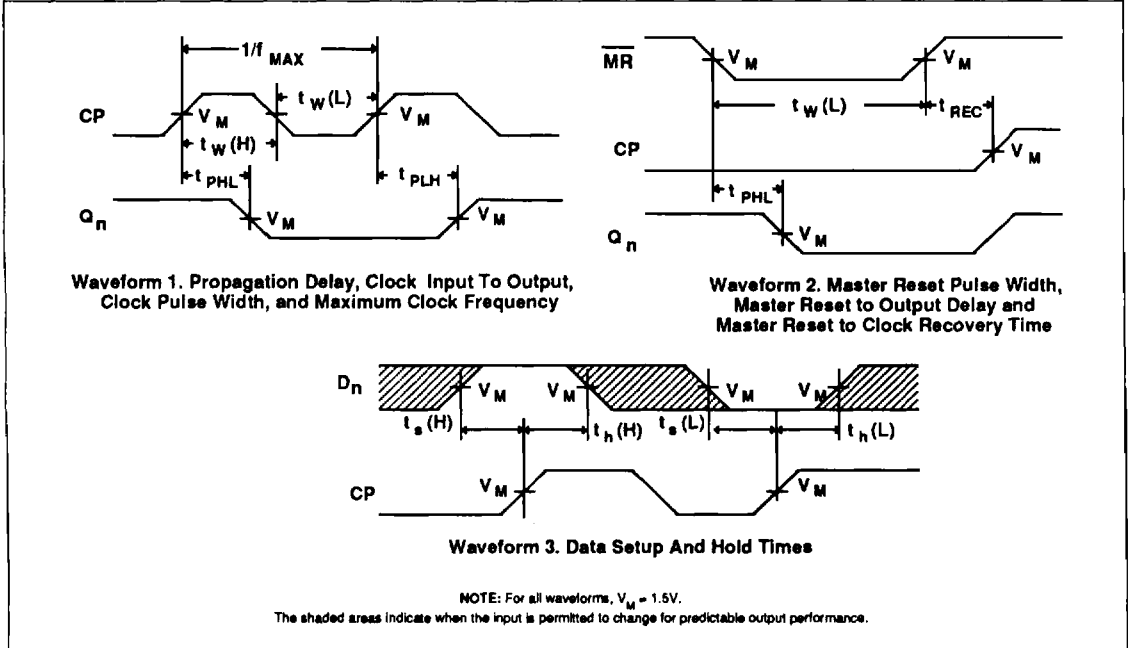
**AC SETUP REQUIREMENTS**

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT
			T <sub>A</sub> = +25°C			T <sub>A</sub> = 0°C to +70°C			
			Min	Typ	Max	Min	Max		
t <sub>s(H)</sub> t <sub>s(L)</sub>	Setup time, High or Low D <sub>n</sub> to CP	Waveform 3	4.0			4.0			ns
			4.0			4.0			
t <sub>h(H)</sub> t <sub>h(L)</sub>	Hold time, High or Low D <sub>n</sub> to CP	Waveform 3	0			0			ns
			0			0			
t <sub>w(H)</sub> t <sub>w(L)</sub>	CP Pulse width, High or Low	Waveform 1	4.0			4.0			ns
			6.0			6.0			
t <sub>w(L)</sub>	$\overline{MR}$ Pulse width, Low	Waveform 2	5.0			5.0		ns	
t <sub>REC</sub>	Recovery time, $\overline{MR}$ to CP	Waveform 2	5.0			5.0		ns	

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AC WAVEFORM



TEST CIRCUIT AND WAVEFORMS

